





萬誠科技股份有限公司

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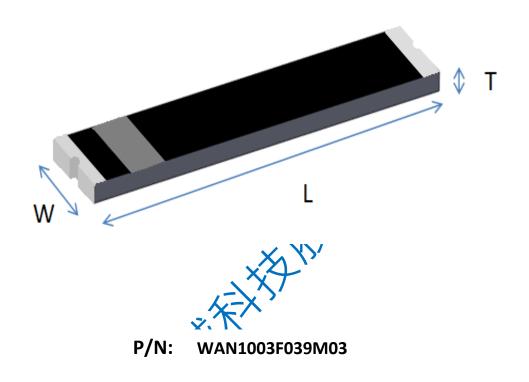
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OneWave Electronic Co., Ltd.

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1003 Chip antenna

For 315 / 433 / 470 / 868 / 915MHz Applications



1		Dimension (mm)
10	L	10.50 ± 0.20
- ner	W	3.00 ± 0.20
	Т	1.23 ± 0.20
N Y		

Part Number Information

W	AN	<u>1003</u>	<u>F</u>	<u>039</u>	M	<u>03</u>	
	Α	В	С	D	Ε	F	
A Product Series			Antenna				
В	B Dimension L x W		10 x 3mm (±0.2mm)				
С	C Material		High K material				
D	D Working Frequency		315MHz / 433MHz / 470MHz 868MHz / 915MHz				
Ε	Feeding mode		Monopole & Single Feeding				
F	Antenna type			Type = 03			
lectrical Specification							

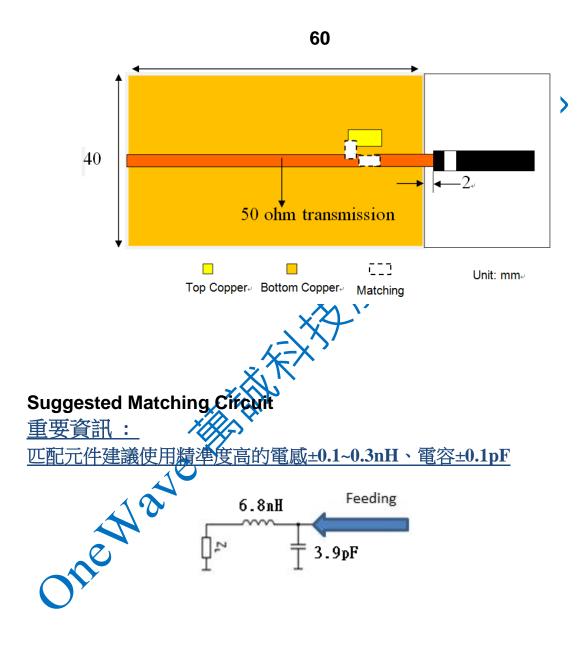
1. Electrical Specification

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Specification				
Part Number WAN1003F039M03				
Central Frequency	315 / 433 / 470 / 868 / 915	MHz		
Bandwidth	25 (Min.)	MHz		
Return Loss	-10 (Max)	dB		
Peak Gain	1.08 / 1.15 / 1.21 / 1.27 / 1.32	dBi		
Impedance	50	Ohm		
Operating Temperature	-40~+110	°C		
Maximum Power	4	W		
Resistance to Soldering Heats	10 (@ 260°C)	sec.		
	I.			
Polarization	Linear			
Azimuth Beamwidth	Omni-directional			
Termination	Cu / Sn (Leadless)			

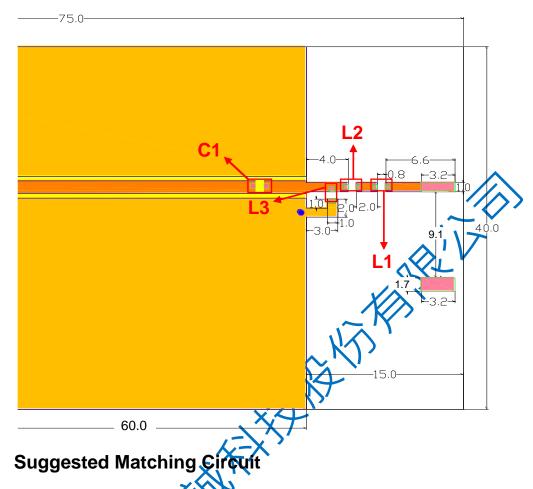
Remark : Bandwidth & Peak Gain was measured under evaluation board of next page

2. Recommended PCB Pattern

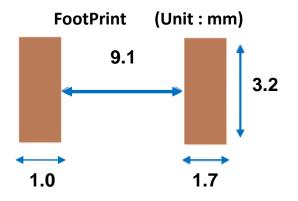
Evaluation Board Dimension



Evaluation Board Dimension

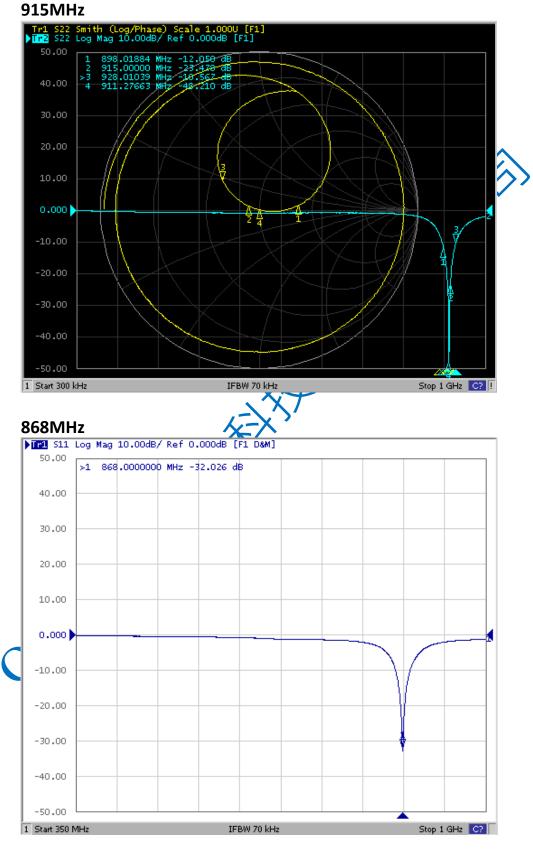


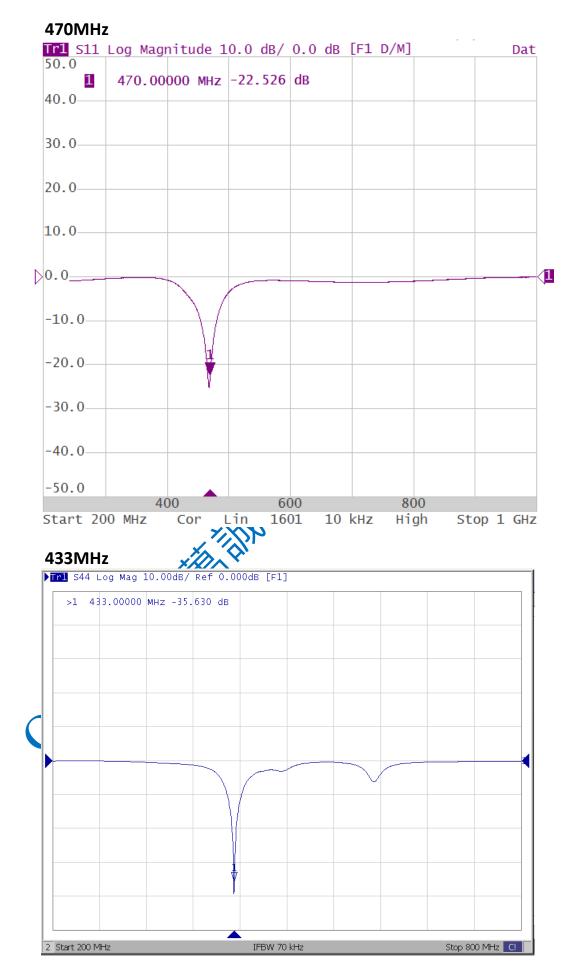
	Inductance[nH]			Capacitance[pF]
Fc [MHz]	L1	L2	L3	C1
315	56	240	30	6.2
433	ΩΟΟ	150	30	3
470	10	120	15	3
868	2	39	8.2	0Ω
915	Ο Ω	36	6.8	0Ω



3. Measurement Results

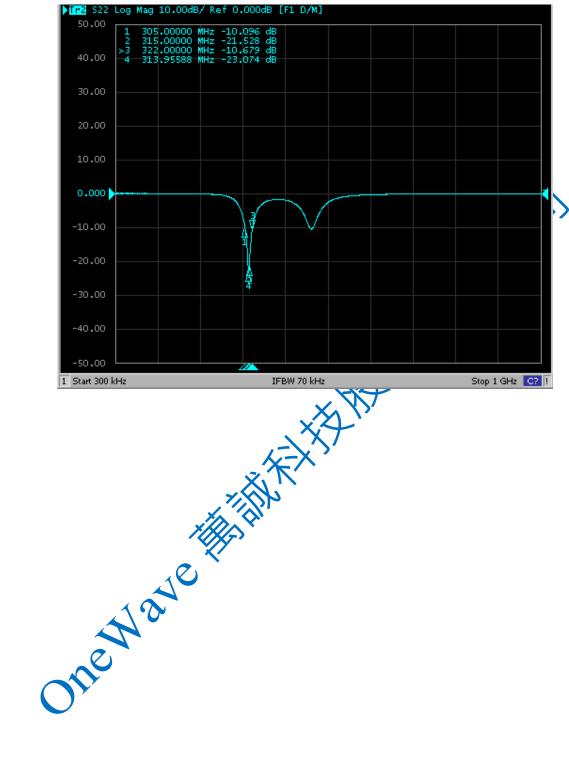
Return Loss



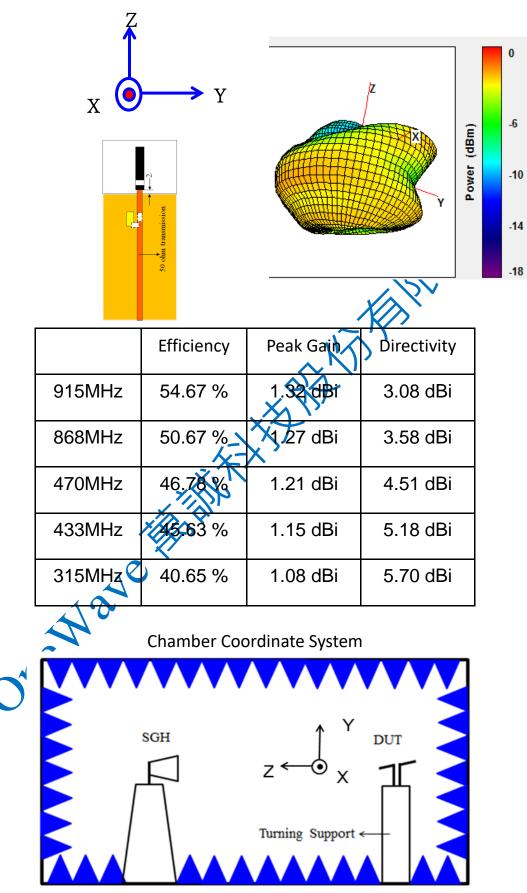


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Radiation Pattern





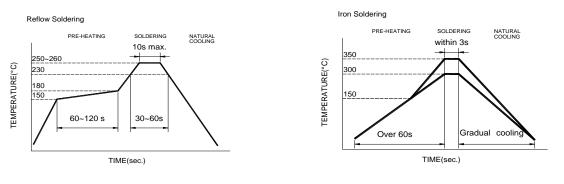
ITEM	REQUIREMENTS	TEST CONDITION		
Solderability	1. Wetting shall exceed 90% coverage	Pre-heating temperature:150°C/60sec.		
	2. No visible mechanical damage	Solder temperature:230 \pm 5 $^{\circ}$ C		
	TEMP (°C)	Duration:4±1sec.		
	230°C4±1 sec.	Solder:Sn-Ag3.0-Cu0.5		
		Flux for lead free: rosin		
	150°C			
	/ 60sec \			
Solder heat	1. No visible mechanical damage	Pre-heating temperature:150°C/60sec.		
Resistance	2. Central Freq. change :within ± 6%	Solder temperature:260±5°		
	TEMP (°C)	Duration:10±0.5sec.		
	10±0.5 sec.	Solder:Sn-Ag3.0-Cu0.5		
	260°C	Flux for lead free: rosin		
	150°C			
	60sec			
Component	1. No visible mechanical damage	The device should be reflow		
Adhesion (Push test)		soldered(230 \pm 5 $^{\circ}$ C for 10sec.) to a tinned		
(Fush lest)		copper substrate A dynometer force		
		gauge should be applied the side of the component. The device must with-ST-F		
		0.5 Kg without failure of the termination		
		attached to component.		
Component	1. No visible mechanical damage	Insert 10cm wire into the remaining open		
Adhesion		eye bend ,the ends of even wire lengths		
(Pull test)	×->	upward and wind together.		
	×, Ν	Terminal shall not be remarkably		
Thermoleheel		damaged. +110℃=>30±3min		
Thermal shock	1. No visible mechanical damage	-40°C =>30±3min		
	2. Central Freq. change :within ±6%	Test cycle:10 cycles		
	Phase Temperature(℃) Time(min)	The chip shall be stabilized at normal		
	1 +110±5℃ 30±3	condition for 2~3 hours before		
	2 Room Within	measuring.		
	Temperature 3sec	-		
	3 -40±2°C 30±3			
	4 Room Within			
	Temperature 3sec			
Resistance to	1. No visible mechanical damage	Temperature: +110±5℃		
High	2. Central Freq. change :within ±6%	Duration: 1000±12hrs		
Temperature	3. No disconnection or short circuit.	The chip shall be stabilized at normal condition for 2~3 hours before		
		measuring.		
Resistance to	1. No visible mechanical damage	Temperature:-40±5°C		
Low	2. Central Freq. change :within ±6%	Duration: 1000±12hrs		
Temperature	3. No disconnection or short circuit.	The chip shall be stabilized at normal condition for 2~3 hours before		
		measuring.		
Humidity	1. No visible mechanical damage	Temperature: 40±2℃		
	2. Central Freq. change :within ±6% 3. No disconnection or short circuit.	Humidity: 90% to 95% RH		
		Duration: 1000±12hrs The chip shall be stabilized at normal		
		condition for 2~3 hours before		
		measuring.		

4. Reliability and Test Condictions

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5.Soldering and Mounting

Mildly activated rosin fluxes are preferred. The minimum amount of solder can lead to damage from the stresses caused by the difference in coefficients of expansion between solder, chip and substrate. The terminations are suitable for all wave and re-flow soldering systems. If hand soldering cannot be avoided, the preferred technique is the utilization of hot air soldering tools.

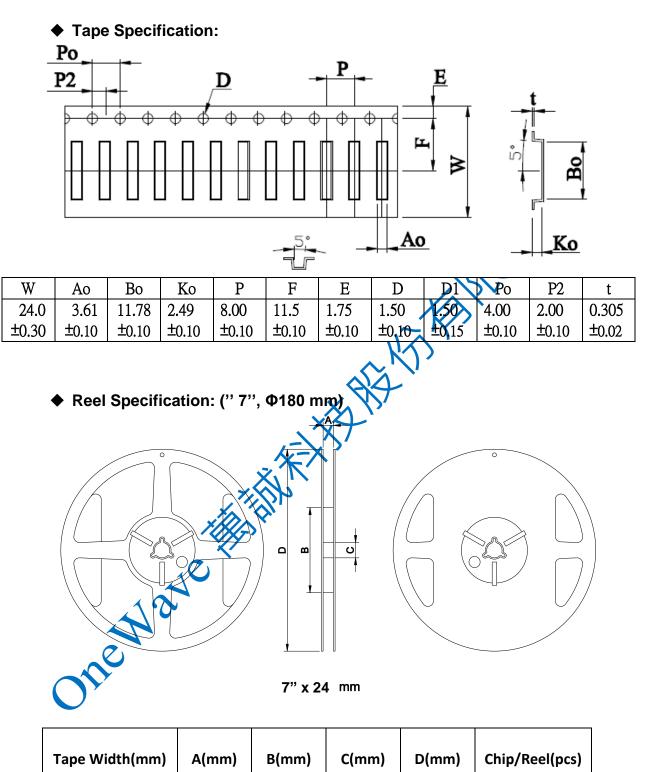


Recommended temperature profiles for retion soldering in Figure 1.

Products attachment with a soldering iron is discouraged due to the inherent process control limitations. In the event that a soldering iron must be employed the following precautions are recommended.

- Preheat circuit and products to $150^\circ C$
- Never contact the ceramic with the iron tip
- Use a 20 wat soldering iron with tip diameter of 1.0mm
- 280°C tip temperature (max)
- Limit soldering time to 3 sec.

6.Packaging Information



24	25±0.5	60±1.0	13.5±0.5	178±1.0	1000

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7. Storage and Transportation Information

Storage Conditions

To maintain the solderability of terminal electrodes:

- 1. Temperature and humidity conditions: -10~ 40 $^\circ \! \mathbb{C}$ and 30~70% RH.
- 2. Recommended products should be used within 6 months from the time of delivery.
- 3. The packaging material should be kept where no chlorine or sulfur exists in the air.

Transportation Conditions

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- 1. Products should be handled with care to avoid damaged contamination from perspiration and skin oils.
- 2. The use of tweezers or vacuum pick up is strongly recommended for individual components.
- 3. Bulk handling should ensure that abrasion and mechanical shock are minimized.